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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, FlexIO, I²C, LINbus, SPI, UART/USART
Peripherals	POR, PWM, WDT
Number of I/O	89
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b SAR; D/A1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k144hat0mllt

Feature comparison

Description Input Multiplexing sheet(s) attached with Reference Manual.

	S32K11x		S32K14x				
Parameter	K116	K118	K142	K144	K146	K148	
Core	Arm® Cortex™-M0+		Arm® Cortex™-M4F				
Frequency	48 MHz		80 MHz (RUN mode) or 112 MHz (HSRUN mode) ¹				
System	IEEE-754 FPU	○			●		
	Cryptographic Services Engine (CSEc) ¹	●			●		
	CRC module	1x			1x		
	ISO 26262	capable up to ASIL-B		capable up to ASIL-B			
	Peripheral speed	up to 48 MHz		up to 112 MHz (HSRUN)			
	Crossbar	●			●		
	DMA	●			●		
	External Watchdog Monitor (EWM)	○			●		
	Memory Protection Unit (MPU)	●			●		
	FIRC CMU	●			○		
	Watchdog	1x			1x		
	Low power modes	●			●		
	HSRUN mode ¹	○			●		
Memory	Number of I/Os	up to 43	up to 58	up to 89	up to 128	up to 156	
	Single supply voltage	2.7 - 5.5 V		2.7 - 5.5 V			
	Ambient Operation Temperature (Ta)	-40°C to +105°C / +125°C		-40°C to +105°C / +125°C			
	Flash	128 KB	256 KB	256 KB	512 KB	1 MB	2 MB ²
	Error Correcting Code (ECC)	●			●		
	System RAM (including FlexRAM and MTB)	17 KB	25 KB	32 KB	64 KB	128 KB	256 KB
	FlexRAM (also available as system RAM)	2 KB		4 KB			
Timer	Cache	○			4 KB		
	EEPROM emulated by FlexRAM ¹	2 KB (up to 32 KB D-Flash)		4 KB (up to 64 KB D-Flash)			See footnote 3
	External memory interface	○		○			QuadSPI incl. HyperBus TM
	Low Power Interrupt Timer (LPIT)	1x			1x		
	FlexTimer (16-bit counter) 8 channels	2x (16)		4x (32)	6x (48)	8x (64)	
Analog	Low Power Timer (LPTMR)	1x			1x		
	Real Time Counter (RTC)	1x			1x		
	Programmable Delay Block (PDB)	1x			2x		
	Trigger mux (TRGMUX)	1x (43)	1x (45)	1x (64)	1x (73)	1x (81)	
Communication	12-bit SAR ADC (1 Msps each)	1x (13)	1x (16)	2x (16)	2x (24)	2x (32)	
	Comparator with 8-bit DAC	1x			1x		
	10/100 Mbps IEEE-1588 Ethernet MAC	○		○		1x	
	Serial Audio Interface (AC97, TDM, I2S)	○		○		2x	
	Low Power UART/LIN (LPUART) (Supports LIN protocol versions 1.3, 2.0, 2.1, 2.2A, and SAE J2602)	2x		2x	3x		
	Low Power SPI (LPSPI)	1x	2x	2x	3x		
	Low Power I2C (LPI2C)	1x			1x		2x
IDEs	FlexCAN (CAN-FD ISO/CD 11898-1)	1x (1x with FD)		2x (1x with FD)	3x (1x with FD)	3x (2x with FD)	3x (3x with FD)
	FlexIO (8 pins configurable as UART, SPI, I2C, I2S)	1x		1x			
Other	Debug & trace	SWD, MTB (1 KB), JTAG ⁴		SWD, JTAG (ITM, SWV, SWO)			SWD, JTAG (ITM, SWV, SWO), ETM
	Ecosystem (IDE, compiler, debugger)	NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems		NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems			
Packages ⁵	32-pin QFN 48-pin LQFP	48-pin LQFP 64-pin LQFP	64-pin LQFP 100-pin LQFP	64-pin LQFP 100-pin LQFP 100-pin MAPBGA 100-pin MAPBGA 144-pin LQFP 144-pin LQFP	64-pin LQFP 100-pin LQFP 100-pin MAPBGA 100-pin MAPBGA 144-pin LQFP 144-pin LQFP	64-pin LQFP 100-pin MAPBGA 100-pin MAPBGA 144-pin LQFP 144-pin LQFP	100-pin MAPBGA 144-pin LQFP 176-pin LQFP

LEGEND:

- Not implemented
 - Available on the device
- 1 No write or erase access to Flash module, including Security (CSEc) and EEPROM commands, are allowed when device is running at HSRUN mode (112MHz) or VLPR mode.
- 2 Available when EEPROM, CSEc and Data Flash are not used. Else only up to 1,984 KB is available for Program Flash.
- 3 4 KB (up to 512 KB D-Flash as a part of 2 MB Flash). Up to 64 KB of flash is used as EEPROM backup and the remaining 448 KB of the last 512 KB block can be used as Data flash or Program flash. See chapter FTFC for details.
- 4 Only for Boundary Scan Register
- 5 See Dimensions section for package drawings

Figure 3. S32K1xx product series comparison

3 Ordering information

3.1 Selecting orderable part number

Not all part number combinations are available. See the attachment *S32K1xx_Orderable_Part_Number_List.xlsx* attached with the Datasheet for a list of standard orderable part numbers.

Table 7. Power consumption (Typicals unless stated otherwise) 1 (continued)

Chip/Device	Ambient Temperature (°C)	VLPS (μ A) ²		VLPR (mA)			STOP1 (mA)	STOP2 (mA)	RUN@48 MHz (mA)		RUN@64 MHz (mA)		RUN@80 MHz (mA)		HSRUN@112 MHz (mA) ³		IDD/MHz (μ A/MHz) ⁴	
		Peripherals disabled ⁵	Peripherals enabled	Peripherals disabled ⁶	Peripherals enabled use case 1 ⁶	Peripherals enabled use case 2 ⁷			Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled		
	105	Max	1660	1736	3.48	3.55	NA	14.5	15.6	34.8	43.6	41.9	53.9	48.7	65.1	70.4	96.1	609
		Typ	560	577	2.49	2.54	4.03	10.9	11.9	29.8	37.8	37.6	47.5	45.2	61.5	63.8	89.1	565
		Max	2945	2970	4.40	4.47	NA	18.0	19.0	38.4	46.8	44.9	55.3	51.6	66.8	73.6	97.4	645
	125	Typ	NA	NA	NA	NA	4.85	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA	719
		Max	3990	4166	6.00	6.08	NA	23.4	24.5	44.3	52.5	50.9	61.3	57.5	71.6	NA	NA	

1. Typical current numbers are indicative for typical silicon process and may vary based on the silicon distribution and user configuration. Typical conditions assumes $V_{DD} = V_{DDA} = V_{REFH} = 5$ V, temperature = 25 °C and typical silicon process unless otherwise stated. All output pins are floating and On-chip pulldown is enabled for all unused input pins.
2. Current numbers are for reduced configuration and may vary based on user configuration and silicon process variation.
3. HSRUN mode must not be used at 125°C. Max ambient temperature for HSRUN mode is 105°C.
4. Values mentioned for S32K14x devices are measured at RUN@80 MHz with peripherals disabled and values mentioned for S32K11x devices are measured at RUN@48 MHz with peripherals disabled.
5. With PMC_REGSC[CLKBIASDIS] set to 1. See Reference Manual for details.
6. Data collected using RAM
7. Numbers on limited samples size and data collected with Flash
8. The S32K148 data points assume that ENET/QuadSPI/SAI etc. are inactive.

5. Several I/O have both high drive and normal drive capability selected by the associated Portx_PCRn[DSE] control bit. All other GPIOs are normal drive only. For details refer to *SK3K144_IO_Signal_Description_Input_Multiplexing.xlsx* attached with the *Reference Manual*.
6. Measured at input V = V_{SS}
7. Measured at input V = V_{DD}

5.5 AC electrical specifications at 3.3 V range

Table 13. AC electrical specifications at 3.3 V Range

Symbol	DSE	Rise time (nS) ¹		Fall time (nS) ¹		Capacitance (pF) ²
		Min.	Max.	Min.	Max.	
tRF _{GPIO}	NA	3.2	14.5	3.4	15.7	25
		5.7	23.7	6.0	26.2	50
		20.0	80.0	20.8	88.4	200
tRF _{GPIO-HD}	0	3.2	14.5	3.4	15.7	25
		5.7	23.7	6.0	26.2	50
		20.0	80.0	20.8	88.4	200
	1	1.5	5.8	1.7	6.1	25
		2.4	8.0	2.6	8.3	50
		6.3	22.0	6.0	23.8	200
tRF _{GPIO-FAST}	0	0.6	2.8	0.5	2.8	25
		3.0	7.1	2.6	7.5	50
		12.0	27.0	10.3	26.8	200
	1	0.4	1.3	0.38	1.3	25
		1.5	3.8	1.4	3.9	50
		7.4	14.9	7.0	15.3	200

1. For reference only. Run simulations with the IBIS model and your custom board for accurate results.
2. Maximum capacitances supported on Standard IOs. However interface or protocol specific specifications might be different, for example for ENET, QSPI etc. For protocol specific AC specifications, see respective sections.

5.6 AC electrical specifications at 5 V range

Table 14. AC electrical specifications at 5 V Range

Symbol	DSE	Rise time (nS) ¹		Fall time (nS) ¹		Capacitance (pF) ²
		Min.	Max.	Min.	Max.	
tRF _{GPIO}	NA	2.8	9.4	2.9	10.7	25
		5.0	15.7	5.1	17.4	50
		17.3	54.8	17.6	59.7	200
tRF _{GPIO-HD}	0	2.8	9.4	2.9	10.7	25
		5.0	15.7	5.1	17.4	50

Table continues on the next page...

Table 16. Device clock specifications 1 (continued)

Symbol	Description	Min.	Max.	Unit
f_{FLASH}	Flash clock	—	24	MHz
Normal run mode (S32K14x series) ³				
f_{SYS}	System and core clock	—	80	MHz
f_{BUS}	Bus clock	—	40 ⁴	MHz
f_{FLASH}	Flash clock	—	26.67	MHz
VLPR mode ⁵				
f_{SYS}	System and core clock	—	4	MHz
f_{BUS}	Bus clock	—	4	MHz
f_{FLASH}	Flash clock	—	1	MHz
f_{ERCLK}	External reference clock	—	16	MHz

1. Refer to the section [Feature comparison](#) for the availability of modes and other specifications.
2. Only available on some devices. See section [Feature comparison](#).
3. With SPLL as system clock source.
4. 48 MHz when f_{SYS} is 48 MHz
5. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

6 Peripheral operating requirements and behaviors

6.1 System modules

There are no electrical specifications necessary for the device's system modules.

6.2 Clock interface modules

6.2.1 External System Oscillator electrical specifications

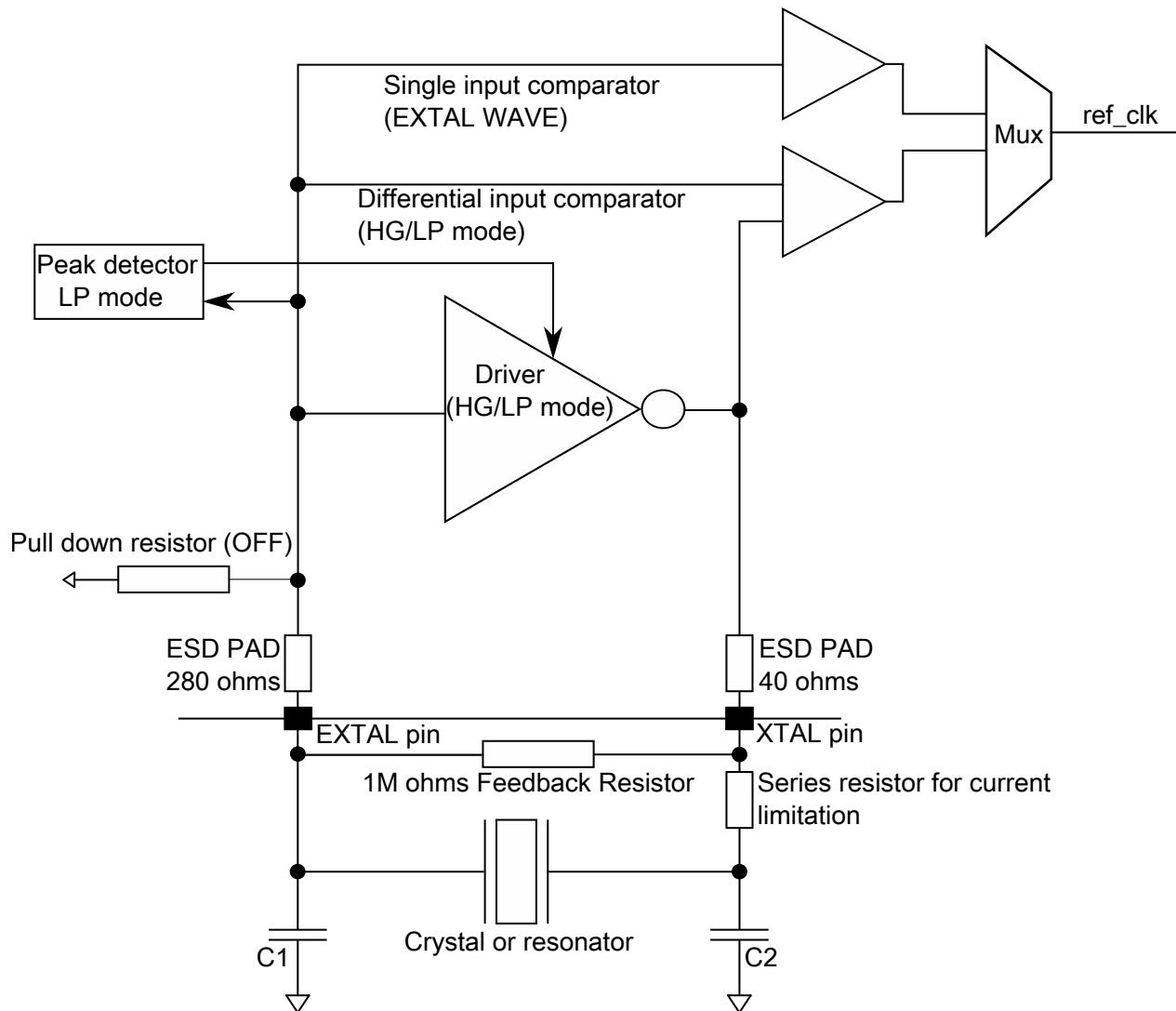


Figure 8. Oscillator connections scheme

Table 17. External System Oscillator electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
$g_{m\text{osc}}$	Crystal oscillator transconductance					
	SCG_SOSCCFG[RANGE]=2'b10 for 4-8 MHz	2.2	—	13.7	mA/V	
	SCG_SOSCCFG[RANGE]=2'b11 for 8-40 MHz	16	—	47	mA/V	
V_{IL}	Input low voltage — EXTAL pin in external clock mode	V_{SS}	—	1.15	V	
V_{IH}	Input high voltage — EXTAL pin in external clock mode	$0.7 * V_{DD}$	—	V_{DD}	V	
C_1	EXTAL load capacitance	—	—	—		1
C_2	XTAL load capacitance	—	—	—		1
R_F	Feedback resistor	—	—	—	$M\Omega$	2
	Low-gain mode (HGO=0)	—	—	—		

Table continues on the next page...

Table 18. External System Oscillator frequency specifications

Symbol	Description	Min.		Typ.		Max.		Unit	Notes
		S32K14x	S32K11x	S32K14x	S32K11x	S32K14x	S32K11x		
f_{osc_hi}	Oscillator crystal or resonator frequency	4		—		40		MHz	
f_{ec_extal}	Input clock frequency (external clock mode)	—		—		50	48	MHz	1
t_{dc_extal}	Input clock duty cycle (external clock mode)	48		50		52		%	1
t_{cst}	Crystal Start-up Time								
	8 MHz low-gain mode (HGO=0)	—		1.5		—		ms	2
	8 MHz high-gain mode (HGO=1)	—		2.5		—			
	40 MHz low-gain mode (HGO=0)	—		2		—			
	40 MHz high-gain mode (HGO=1)	—		2		—			

1. Frequencies below 40 MHz can be used for degraded duty cycle upto 40-60%
2. Proper PC board layout procedures must be followed to achieve specifications.

6.2.3 System Clock Generation (SCG) specifications

6.2.3.1 Fast internal RC Oscillator (FIRC) electrical specifications

Table 19. Fast internal RC Oscillator electrical specifications

Symbol	Parameter ¹	Value			Unit
		Min.	Typ.	Max.	
F_{FIRC}	FIRC target frequency	—	48	—	MHz
ΔF	Frequency deviation across process, voltage, and temperature < 105°C	—	± 0.5	± 1	% F_{FIRC}
ΔF_{125}	Frequency deviation across process, voltage, and temperature < 125°C	—	± 0.5	± 1.1	% F_{FIRC}
T_{Startup}	Startup time	—	3.4	5	μs^2
$T_{\text{JIT}}^{\text{3}}$	Cycle-to-Cycle jitter	—	300	500	ps
$T_{\text{JIT}}^{\text{3}}$	Long term jitter over 1000 cycles	—	0.04	0.1	% F_{FIRC}

- With FIRC regulator enable
- Startup time is defined as the time between clock enablement and clock availability for system use.
- FIRC as system clock

NOTE

Fast internal RC Oscillator is compliant with CAN and LIN standards.

6.2.3.2 Slow internal RC oscillator (SIRC) electrical specifications

Table 20. Slow internal RC oscillator (SIRC) electrical specifications

Symbol	Parameter	Value			Unit
		Min.	Typ.	Max.	
F_{SIRC}	SIRC target frequency	—	8	—	MHz
ΔF	Frequency deviation across process, voltage, and temperature < 105°C	—	—	± 3	% F_{SIRC}
ΔF_{125}	Frequency deviation across process, voltage, and temperature < 125°C	—	—	± 3.3	% F_{SIRC}
T_{Startup}	Startup time	—	9	12.5	μs^1

- Startup time is defined as the time between clock enablement and clock availability for system use.

Table 26. QuadSPI electrical specifications (continued)

FLASH PORT	Sym	Unit	FLASH A												FLASH B					
			RUN ¹						HSRUN ¹						RUN/HSRUN ²					
			SDR						SDR						SDR			DDR ³		
			Internal Sampling			Internal DQS			Internal Sampling			Internal DQS			Internal Sampling			External DQS		
			N1		PAD Loopback		Internal Loopback		N1		PAD Loopback		Internal Loopback		N1		External DQS			
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
SCK Duty Cycle	t _{SDC}	ns	tSCK2 + 2.5		tSCK2 - 2.5		tSCK2 + 1.5		tSCK2 - 1.5		tSCK2 + 0.750		tSCK2 + 1.5		tSCK2 - 1.5		tSCK2 + 1.5		tSCK2 - 1.5	
Data Input Setup Time	t _{SI}	ns	15	-	2.5	-	10	-	14	-	1.6	-	6	-	25	-	2	-	-	-
Data Input Hold Time	t _{HI}	ns	0	-	1	-	1	-	0	-	1	-	1	-	0	-	20	-	-	-
Data Output Valid Time	t _{OV}	ns	-	4.5	-	4.5	-	4.5	-	-	4	-	4	-	4	-	-	10	-	10
Data Output In-Valid Time	t _{IV}	ns	-	5	-	5	-	5	-	5	-	5	-	3 ⁵	-	5	-	5	-	5
CS to SCK Time ⁶	t _{cssck}	ns	5	-	5	-	5	-	5	-	5	-	5	-	5	-	10	-	10	-
SCK to CS Time ⁷	t _{sckcs}	ns	5	-	5	-	5	-	5	-	5	-	5	-	5	-	5	-	5	-
Output Load		pf	25		25		25		25		25		25		25		25		25	

1. See Reference Manual for details on mode settings
2. See Reference Manual for details on mode settings
3. Valid for HyperRAM only
4. RWDS(External DQS CLK) frequency
5. For operating frequency ≤ 64 Mhz, Output invalid time is 5 ns.
6. Program register value QuadSPI_FLSHCR[TCSS] = 4'h2
7. Program register value QuadSPI_FLSHCR[TCSH] = 4'h1

6.4.1.2 12-bit ADC electrical characteristics

NOTE

- ADC performance specifications are documented using a single ADC. For parallel/simultaneous operation of both ADCs, either for sampling the same channel by both ADCs or for sampling different channels by each ADC, some amount of decrease in performance can be expected. Care must be taken to stagger the two ADC conversions, in particular the sample phase, to minimize the impact of simultaneous conversions.
- On reduced pin packages where ADC reference pins are shared with supply pins, ADC analog performance characteristics may be impacted. The amount of variation will be directly impacted by the external PCB layout and hence care must be taken with PCB routing. See [AN5426](#) for details

Table 28. 12-bit ADC characteristics (2.7 V to 3 V) ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SS}$)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
V_{DDA}	Supply voltage		2.7	—	3	V	
I_{DDA_ADC}	Supply current per ADC		—	0.6	—	mA	³
SMPLTS	Sample Time		275	—	Refer to the Reference Manual	ns	
TUE ⁴	Total unadjusted error		—	± 4	± 8	LSB ⁵	^{6, 7, 8, 9}
DNL	Differential non-linearity		—	± 1.0	—	LSB ⁵	^{6, 7, 8, 9}
INL	Integral non-linearity		—	± 2.0	—	LSB ⁵	^{6, 7, 8, 9}

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH}=V_{DDA}=V_{DD}$, with the calibration frequency set to less than or equal to half of the maximum specified ADC clock frequency.
2. Typical values assume $V_{DDA} = 3$ V, Temp = 25 °C, $f_{ADCK} = 40$ MHz, $R_{AS}=20\ \Omega$, and $C_{AS}=10\ nF$.
3. The ADC supply current depends on the ADC conversion rate.
4. Represents total static error, which includes offset and full scale error.
5. $1\ LSB = (V_{REFH} - V_{REFL})/2^N$
6. The specifications are with averaging and in standalone mode only. Performance may degrade depending upon device use case scenario. When using ADC averaging, refer to the *Reference Manual* to determine the most appropriate settings for AVGS.
7. For ADC signals adjacent to V_{DD}/V_{SS} or XTAL/EXTAL or high frequency switching pins, some degradation in the ADC performance may be observed.
8. All values guarantee the performance of the ADC for multiple ADC input channel pins. When using ADC to monitor the internal analog parameters, assume minor degradation.
9. All the parameters in the table are given assuming system clock as the clocking source for ADC.

6.4.2 CMP with 8-bit DAC electrical specifications

Table 31. Comparator with 8-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
I_{DDHS}	Supply current, High-speed mode ¹				μA
	-40 - 125 °C	—	230	300	
I_{DDLS}	Supply current, Low-speed mode ¹				μA
	-40 - 105 °C	—	6	11	
	-40 - 125 °C		6	13	
V_{AIN}	Analog input voltage	0	0 - V_{DDA}	V_{DDA}	V
V_{AIO}	Analog input offset voltage, High-speed mode				mV
	-40 - 125 °C	-25	± 1	25	
V_{AOI}	Analog input offset voltage, Low-speed mode				mV
	-40 - 125 °C	-40	± 4	40	
t_{DHSB}	Propagation delay, High-speed mode ²				ns
	-40 - 105 °C	—	35	200	
	-40 - 125 °C		35	300	
t_{DLSB}	Propagation delay, Low-speed mode ²				μs
	-40 - 105 °C	—	0.5	2	
	-40 - 125 °C	—	0.5	3	
t_{DHSS}	Propagation delay, High-speed mode ³				ns
	-40 - 105 °C	—	70	400	
	-40 - 125 °C	—	70	500	
t_{DLSS}	Propagation delay, Low-speed mode ³				μs
	-40 - 105 °C	—	1	5	
	-40 - 125 °C	—	1	5	
t_{IDHS}	Initialization delay, High-speed mode ⁴				μs
	-40 - 125 °C	—	1.5	3	
t_{IDLS}	Initialization delay, Low-speed mode ⁴				μs
	-40 - 125 °C	—	10	30	
V_{HYST0}	Analog comparator hysteresis, Hyst0				mV
	-40 - 125 °C	—	0	—	
V_{HYST1}	Analog comparator hysteresis, Hyst1, High-speed mode				mV
	-40 - 125 °C	—	19	66	
	Analog comparator hysteresis, Hyst1, Low-speed mode				
	-40 - 125 °C	—	15	40	
V_{HYST2}	Analog comparator hysteresis, Hyst2, High-speed mode				mV
	-40 - 125 °C	—	34	133	

Table continues on the next page...

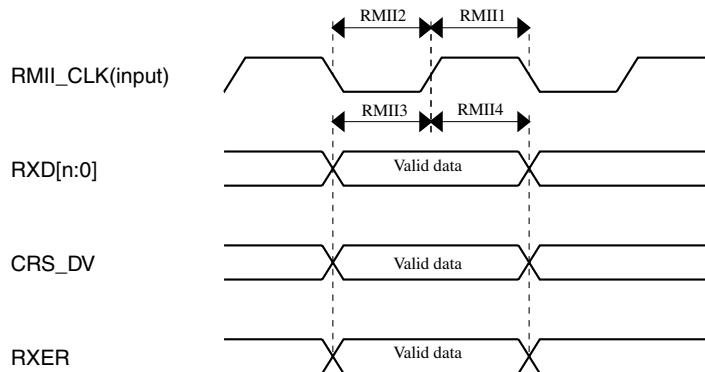
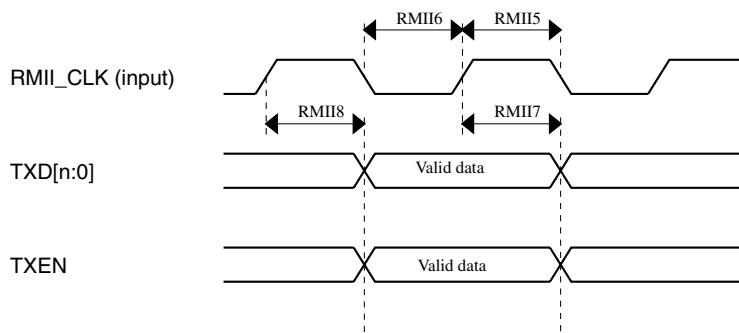
Table 32. LPSPI electrical specifications¹ (continued)

Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit	
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO			
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
8	t _a	Slave access time	Slave	-	50	-	50	-	50	-	50	-	100	-	100	ns	
9	t _{dis}	Slave MISO (SOUT) disable time	Slave	-	50	-	50	-	50	-	50	-	100	-	100	ns	
10	t _v	Data valid (after SPSCK edge)	Slave	-	30	-	39	-	26	-	36 ¹¹ 31 ¹²	-	92	-	96	ns	
			Master	-	12	-	16	-	11	-	15	-	47	-	48		
			Master Loopback ⁵	-	12	-	16	-	11	-	15	-	47	-	48		
			Master Loopback(slow) ⁶	-	8	-	10	-	7	-	9	-	44	-	44		
11	t _{HO}	Data hold time(outputs)	Slave	4	-	4	-	4	-	4	-	4	-	4	-	ns	
			Master	-15	-	-22	-	-15	-	-23	-	-22	-	-29	-		
			Master Loopback ⁵	-10	-	-14	-	-10	-	-14	-	-14	-	-19	-		
			Master Loopback(slow) ⁶	-15	-	-22	-	-15	-	-22	-	-21	-	-27	-		
12	t _{RI/FI}	Rise/Fall time input	Slave	-	1	-	1	-	1	-	1	-	1	-	1	ns	
			Master	-		-		-		-		-		-			
			Master Loopback ⁵	-		-		-		-		-		-			
			Master Loopback(slow) ⁶	-		-		-		-		-		-			
13	t _{RO/FO}	Rise/Fall time output	Slave	-	25	-	25	-	25	-	25	-	25	-	25	ns	
			Master	-		-		-		-		-		-			
			Master Loopback ⁵	-		-		-		-		-		-			

Table continues on the next page...

**Table 36. RMII signal switching specifications
(continued)**

Symbol	Description	Min.	Max.	Unit
RMII7	RMII_CLK to TXD[1:0], TXEN invalid	2	—	ns
RMII8	RMII_CLK to TXD[1:0], TXEN valid	—	15	ns

**Figure 26. RMII receive diagram****Figure 27. RMII transmit diagram**

The following table describes the MDIO electrical characteristics.

- Measurements are with maximum output load of 25 pF, input transition of 1 ns and pad configured with fastest slew settings (DSE = 1'b1).
- I/O operating voltage ranges from 2.97 V to 3.6 V
- While doing the mode transition (RUN -> HSRUN or HSRUN -> RUN), the interface should be OFF.
- MDIO pin must have external Pull-up.

Table 37. MDIO timing specifications

Symbol	Description	Min.	Max.	Unit
—	MDC Clock Frequency	—	2.5	MHz

Table continues on the next page...

Table 38. SWD electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit	
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO			
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
S1	SWD_CLK frequency of operation	-	25	-	25	-	25	-	25	-	10	-	10	MHz	
S2	SWD_CLK cycle period	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	ns	
S3	SWD_CLK clock pulse width					S2/Z + 5	S2/Z - 5	S2/Z + 5	S2/Z - 5	S2/Z + 5	S2/Z - 5	S2/Z + 5	S2/Z - 5	ns	
S4	SWD_CLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns	
S9	SWD_DIO input data setup time to SWD_CLK rise	4	-	4	-	4	-	4	-	16	-	16	-	ns	
S10	SWD_DIO input data hold time after SWD_CLK rise	3	-	3	-	3	-	3	-	10	-	10	-	ns	
S11	SWD_CLK high to SWD_DIO data valid	-	28	-	38	-	28	-	38	-	70	-	77	ns	
S12	SWD_CLK high to SWD_DIO high-Z	-	28	-	38	-	28	-	38	-	70	-	77	ns	
S13	SWD_CLK high to SWD_DIO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns	

Table 40. JTAG electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit	
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO			
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
J1	TCLK frequency of operation													MHz	
	Boundary Scan	-	20	-	20	-	20	-	20	-	10	-	10		
	JTAG	-	20	-	20	-	20	-	20	-	10	-	10		
J2	TCLK cycle period	1/J1	-	1/J1	-	1/J1	-	1/J1	-	1/J1	-	1/J1	-	ns	
J3	TCLK clock pulse width													ns	
	Boundary Scan	5	5	5	5	5	5	5	5	5	5	5	5		
	JTAG	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5		
J4	TCLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns	
J5	Boundary scan input data setup time to TCLK rise	5	-	5	-	5	-	5	-	5	-	15	-	ns	
J6	Boundary scan input data hold time after TCLK rise	5	-	5	-	5	-	5	-	5	-	8	-	ns	
J7	TCLK low to boundary scan output data valid	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J8	TCLK low to boundary scan output data invalid	0	-	0	-	0	-	0	-	0	-	0	-		
J9	TCLK low to boundary scan output high-Z	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J10	TMS, TDI input data setup time to TCLK rise	3	-	3	-	3	-	3	-	15	-	15	-	ns	
J11	TMS, TDI input data hold time after TCLK rise	2	-	2	-	2	-	2	-	8	-	8	-	ns	
J12	TCLK low to TDO data valid	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J13	TCLK low to TDO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns	
J14	TCLK low to TDO high-Z	-	28	-	32	-	28	-	32	-	80	-	80	ns	

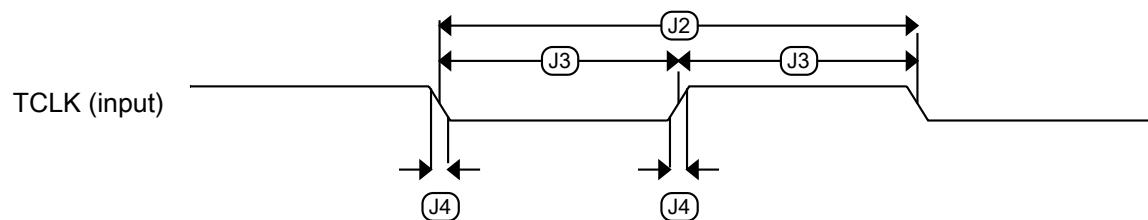


Figure 32. Test clock input timing

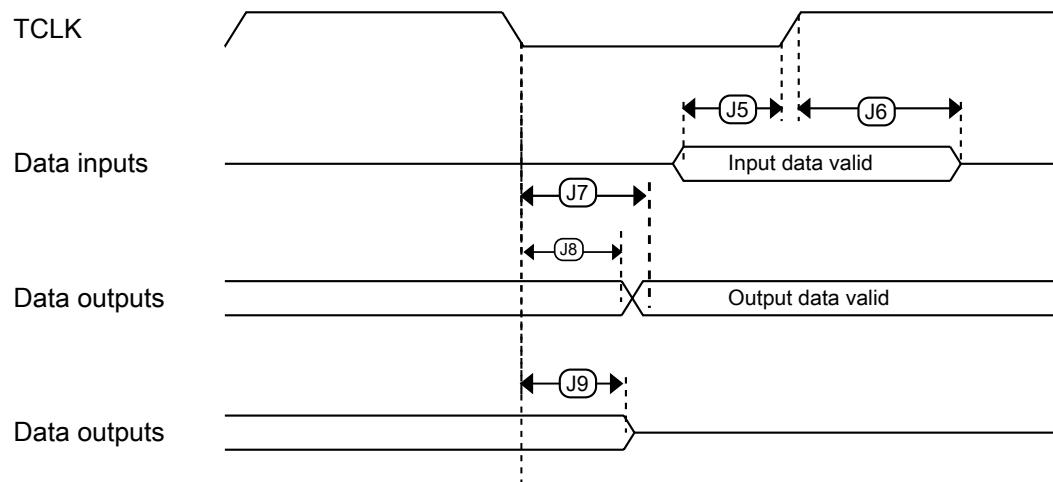


Figure 33. Boundary scan (JTAG) timing

Table 41. Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package (continued)

Rating	Conditions	Symbol	Package	Values						Unit
				S32K116	S32K118	S32K142	S32K144	S32K146	S32K148	
			144	NA	NA	NA	NA	37	31	
			176	NA	NA	NA	NA	NA	30	
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1,3}	Four layer board (2s2p)	$R_{\theta JMA}$	32	26	NA	NA	NA	NA	NA	
			48	48	41	NA	NA	NA	NA	
			64	NA	37	36	36	35	NA	
			100	NA	NA	34	34	33	NA	
			144	NA	NA	NA	NA	36	30	
			176	NA	NA	NA	NA	NA	29	
Thermal resistance, Junction to Board ⁴	—	$R_{\theta JB}$	32	11	NA	NA	NA	NA	NA	
			48	33	24	NA	NA	NA	NA	
			64	NA	26	25	25	23	NA	
			100	NA	NA	25	25	24	NA	
			144	NA	NA	NA	NA	30	24	
			176	NA	NA	NA	NA	NA	24	
Thermal resistance, Junction to Case ⁵	—	$R_{\theta JC}$	32	NA	NA	NA	NA	NA	NA	
			48	23	19	NA	NA	NA	NA	
			64	NA	14	13	12	11	NA	
			100	NA	NA	13	12	11	NA	
			144	NA	NA	NA	NA	12	9	
			176	NA	NA	NA	NA	NA	9	
Thermal resistance, Junction to Case (Bottom) ⁶	—	$R_{\theta JCBottom}$	32	1	NA					
			48	NA						
			64	NA						
			100	NA						
			144	NA						
			176	NA						

Table continues on the next page...

Table 43. Revision History (continued)

Rev. No.	Date	Substantial Changes
		<ul style="list-style-type: none"> • Fixed the typo in R_{SW1} • In LPSPI electrical specifications : <ul style="list-style-type: none"> • Updated t_{Lead} and t_{Lag} • Added footnote in Figure: LPSPI slave mode timing ($CPHA = 0$) and Figure: LPSPI slave mode timing ($CPHA = 1$) • In Thermal characteristics : <ul style="list-style-type: none"> • Updated the name of table: Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package • Deleted specs for $R_{\theta JC}$ for 32 QFN package • Added '$R_{\theta JCBottom}$'
8	18 June 2018	<ul style="list-style-type: none"> • In attachment 'S32K1xx_Power_Modes_Configuration': <ul style="list-style-type: none"> • Updated VLPR peripherals disabled and Peripherals Enabled use case #1, using 4 MHz for System clock, 2 MHz for bus clock, and 1MHz for flash. • Removed S32K116 from Notes • In figure: S32K1xx product series comparison : <ul style="list-style-type: none"> • Added note 'Availability of peripherals depends on the pin availability ...' • Updated 'Ambient Operation Temperature' row • Updated 'System RAM (including FlexRAM and MTB)' row for S32K144, S32K146, and S32K148 • In Ordering information : <ul style="list-style-type: none"> • Updated figure for 'Y: Optional feature' • Updated footnote 3 • In Power and ground pins : <ul style="list-style-type: none"> • In figure 'Power diagram', updated V_{Flash} frequency to 3.3 V • In Power mode transition operating behaviors : <ul style="list-style-type: none"> • Updated footnote for 'VLPS Mode: All clock sources disabled' • In Power consumption : <ul style="list-style-type: none"> • Added IDDs for S32K116 • Added VLPR Peripherals enabled use case 2 at 125 °C/Typicals • Renamed VLPR 'Peripherals enabled' to 'Peripherals enabled use case 1' • Added footnote 'Data collected using RAM' to VLPR 'Peripherals disabled' and VLPR 'Peripherals enabled use case 1' • Updated VLPS Peripherals enabled at 25 °C/Typicals for S32K142 and S32K144 to 40 μA and 42 μA respectively • Added table 'VLPS additional use-case power consumption at typical conditions' • In DC electrical specifications at 3.3 V Range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In DC electrical specifications at 5.0 V Range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In AC electrical specifications at 3.3 V range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In AC electrical specifications at 5 V range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In External System Oscillator electrical specifications : <ul style="list-style-type: none"> • Clarified description of g_{mXosc} • Updated V_{IL} max. to 1.15 V • In Fast internal RC Oscillator (FIRC) electrical specifications :

Revision History

Table 43. Revision History

Rev. No.	Date	Substantial Changes
		<ul style="list-style-type: none">• Updated specs for T_{JIT} Cycle-to-Cycle jitter to 300 ps• In QuadSPI AC specifications :<ul style="list-style-type: none">• Updated specs for T_{iv} Data Output In-Valid Time• In figure 'QuadSPI output timing (SDR mode) diagram', marked Invalid area• In CMP with 8-bit DAC electrical specifications :<ul style="list-style-type: none">• Removed '(VAIO)' from description of V_{HYST0}• In LPSPI electrical specifications :<ul style="list-style-type: none">• Added note 'Undefined' in figures 'LPSPI slave mode timing (CPHA = 0)' and 'LPSPI slave mode timing (CPHA = 1)'



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